



Sandia
National
Laboratories

Exceptional service in the national interest

Silicon nitride crystallization study via molecular dynamics and the **ultra-fast 3-body (UF3)** machine-learned interatomic potential

Tesia D. Janicki¹, Jason Gibson², Carlos Chacon¹, Edwin Chiu¹,
Scott Grutzik¹, Khalid Hattar³, Paul Kotula¹, Hojun Lim¹, Calvin
Parkin¹, Jennie Podlevsky¹, Aashique Rezwan¹, Richard Hennig²,
Chris Bishop¹, J. Matthew D. Lane¹

¹Sandia National Laboratories

²University of Florida

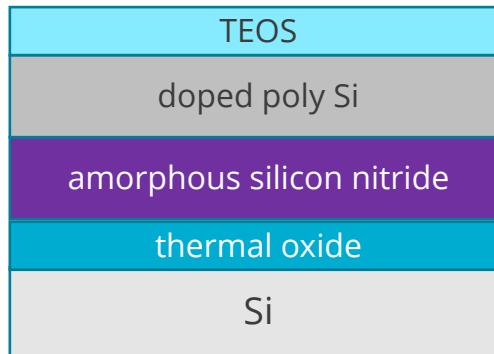
³University of Tennessee-Knoxville

7 March 2024

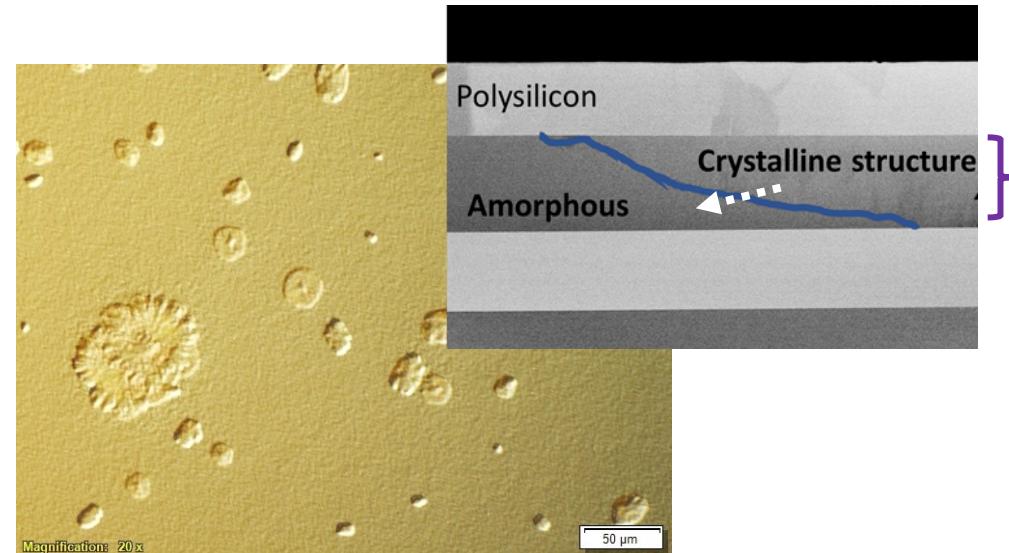
APS March Meeting, Minneapolis, MN

Silicon nitride in microelectronics

Silicon nitride is ubiquitous in microelectronics fabrication across industry.



Anneal at
 $T > 1300\text{K}$



Christopher Bishop, et al. Experimental characterization and modification of Silicon Nitride crystallization reaction kinetics for microelectronics applications. *EMC June 2023*

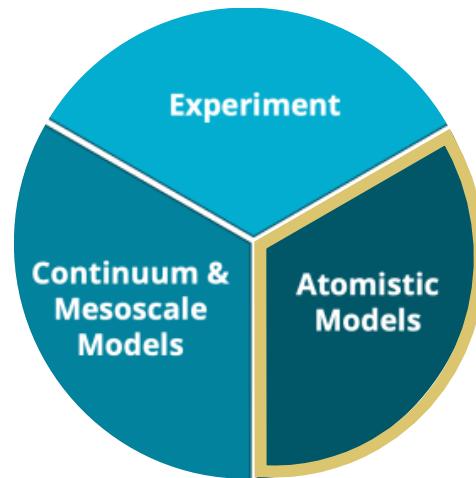
Spurious crystallization of Si_3N_4 occurs at lower temperatures in layer stack than in bulk films.

These effects can be mitigated via temperature control.

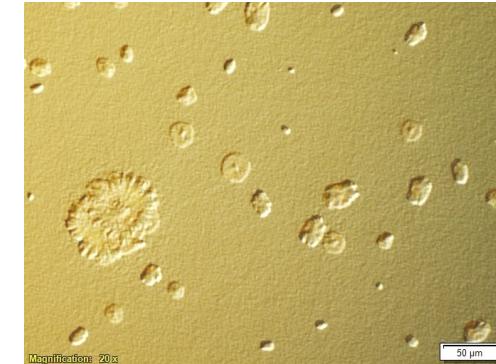
Core science questions regarding the nature of crystallization remain.

- What causes nucleation?
- What is the growth mechanism (e.g. rates)?
- What parameters offer mechanistic control (e.g. stress, composition)?
- Can we model/predict these phenomena?

Interdisciplinary Approach



- What causes nucleation?
- What is the growth mechanism?
- What parameters offer mechanistic control?
- Can we model/predict these phenomena?



Goals for Atomistic Models

- Accurately model structural properties in silicon nitride.
- Show that we can reproduce experimental growth behaviors.
- Extract mechanistic details where possible.

Ultra-Fast 3-Body
(UF3)

Silicon Nitride System: Experiment and MD Approaches



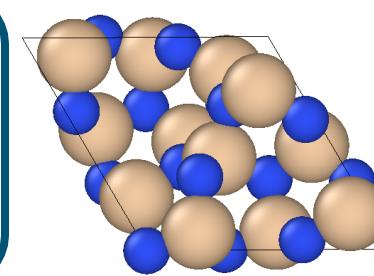
Crystal

Stoichiometric Si_3N_4 possesses 2 stable trigonal polymorphs at ambient pressure.

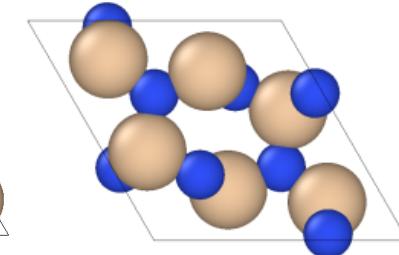
Experiments only observe α nucleation & growth.

Simulations only seed for the α phase in our models.

$\alpha - \text{Si}_3\text{N}_4$



$\beta - \text{Si}_3\text{N}_4$



Amorphous Structure

Experiments use chemical vapor deposition (CVD) to deposit amorphous films.

Simulations use a melt/quench to generate the amorphous phase.**

In ambient pressure, Si_3N_4 dissociates near the melting point.



Interface Dynamics & Crystal Growth

Rates of experimental crystallization near 1400K are $\sim 10^{-8}$ m/s

Simulations use high temperature MD simulations and extrapolate to experimental temperatures using time/temperature superposition.

Interatomic Potentials

Empirical potentials are trained for specific problems and often lack transferability.

Marian, Gastreich & Gale: MG2¹

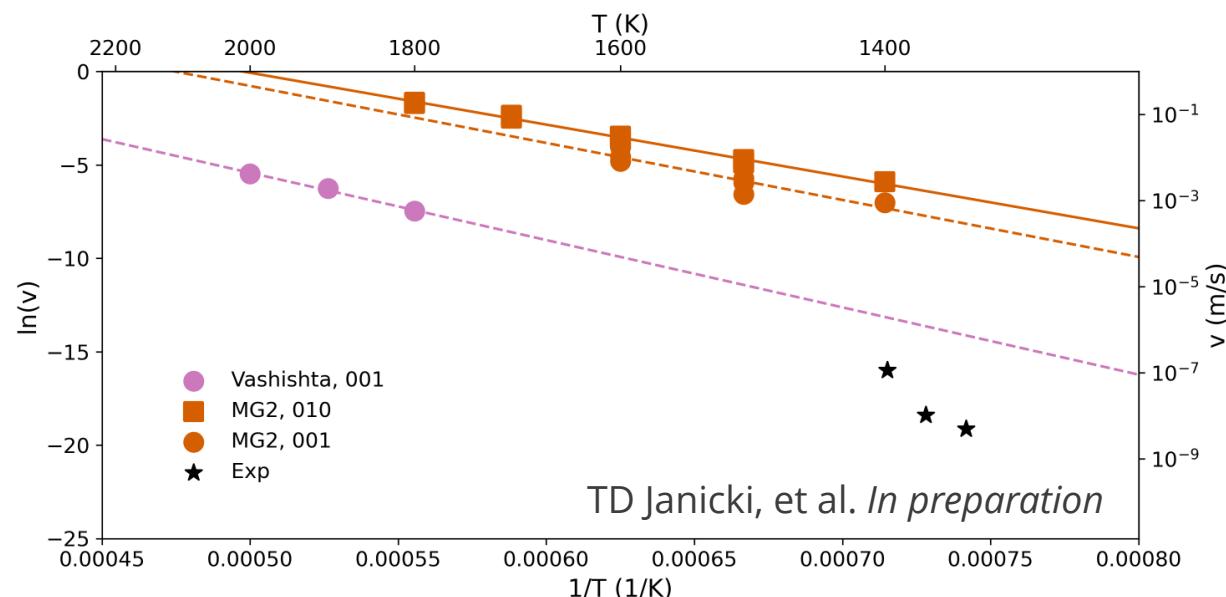
- 2-body
- Designed for structure in SiN and Si-B-N
- Performs well for amorphous structural properties

Vashishta²

- 3-body
- Designed for fracture problems
- Performs well for crystal mechanical properties

$$\ln(\mathbf{v}) = \ln(v_o) - \left(\frac{E_a}{R}\right) \frac{1}{T}$$

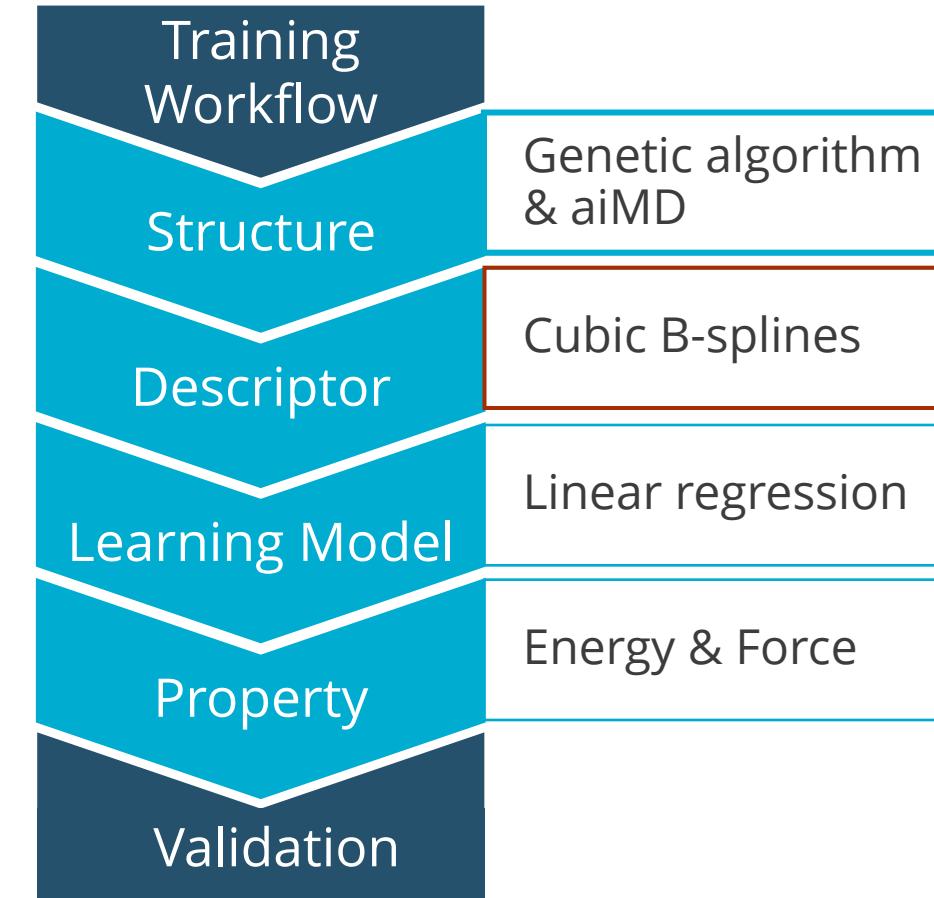
T : temperature
 \mathbf{v} : velocity
 E_a : activation energy



[1] C. M. Marian, M. Gastreich and J. D. Gale. *Phys. Rev. B*. **62** (2000) 3117-3124

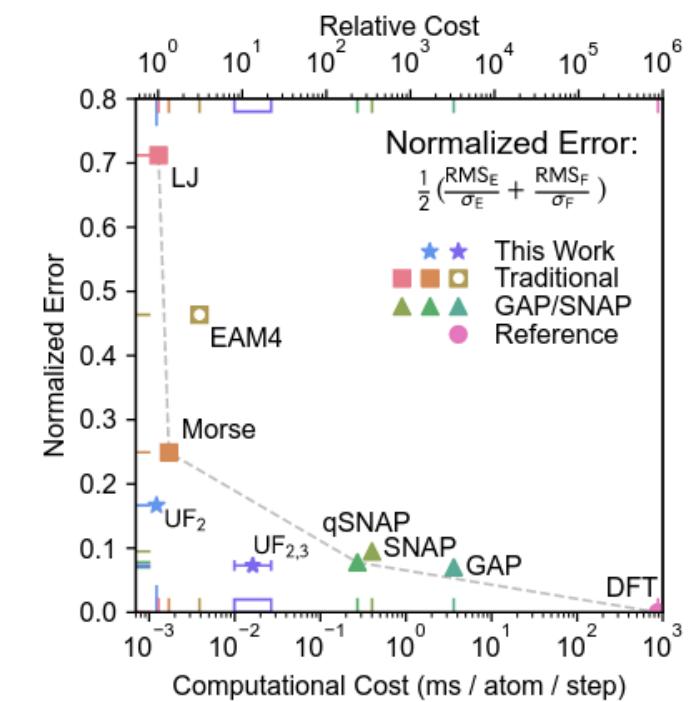
[2] P. Vashishta, R. K. Kalia, A. Nakano, W. Li and I. Ebbsjö. in *Amorphous Insulators and Semiconductors*, edited by M. F. Thorpe and M. I. Mitkova (Kluwer Academic, Netherlands 1997) 151-213

UF3 Development



$$\begin{aligned}
 E &= \sum_{ij} V_2(r_{ij}) + \sum_{ijk} V_3(r_{ijk}) \\
 V_2(r_{ij}) &= \sum_{n=0}^K c_n B_n(r_{ij}) \\
 V_3(r_{ijk}) &= \sum_{l=0}^{K_l} \sum_{m=0}^{K_m} \sum_{n=0}^{K_n} c_{lmn} B_l(r_{ij}) B_m(r_{ik}) B_n(r_{jk}) \\
 B_n &= B_{n,3+1}(r) = \frac{r-t_n}{t_{n+d}-t_n} B_{n,3}(r) \\
 &\quad + \frac{t_{n+d+1}-r}{t_{n+d+1}-t_{n+1}} B_{n+1,3}(r)
 \end{aligned}$$

Performance for 128-atom system of BCC Tungsten:



S. R. Xie, M. Rupp and R. G. Hennig.
NPJ Comput. Mater. **9**, 162 (2023)

Parameters are interpretable, with force and energy mapped back to 2/3-body contributions
UF potentials show promise in both accuracy and efficiency

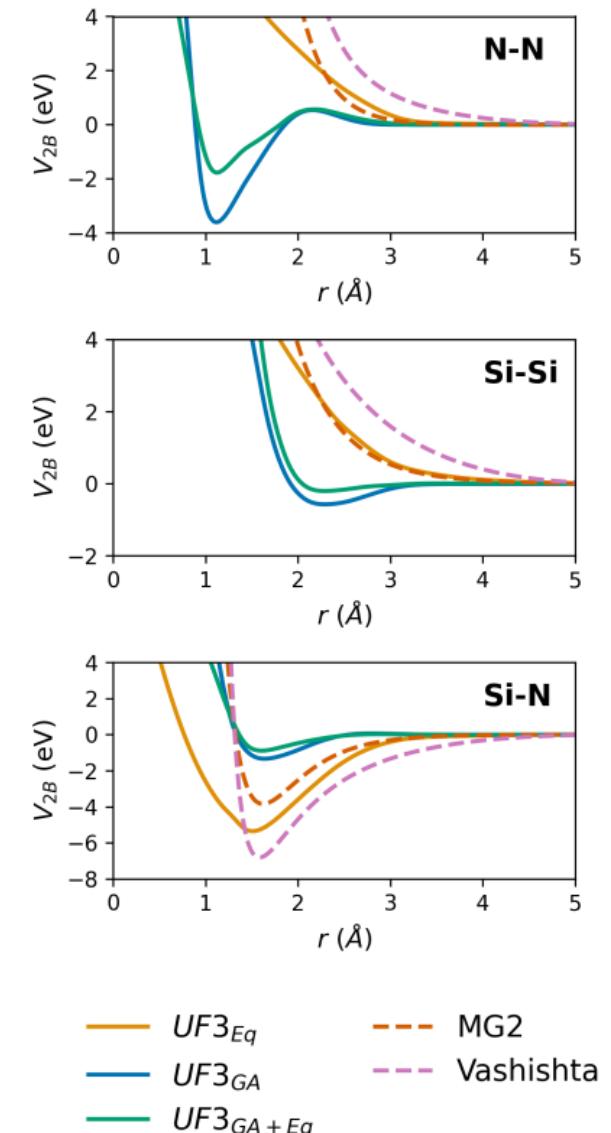
Training UF3

Empirical potentials (**MG2** & **Vashishta**) are trained using a finite set of near-equilibrium structures.

Using near-equilibrium training data (Eq) from *ab initio* Molecular Dynamics, **UF3_{Eq}** shows similar features to empirical models.

Training with non-3:4 structures generated by a genetic algorithm (GA) explores additional phase space in **UF3_{GA}**.

UF3_{GA+Eq} combination of these training sets, retains equilibrium features while allowing investigation of phase space not previously possible.



Crystal Properties

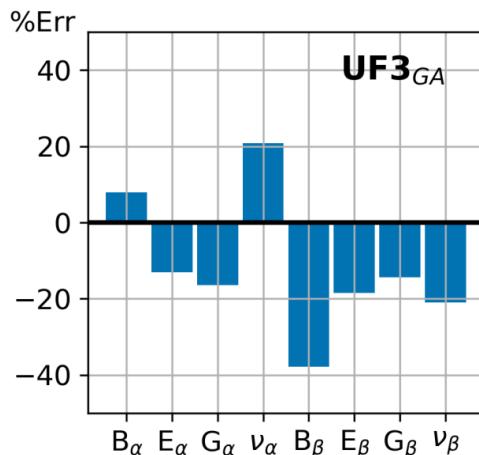
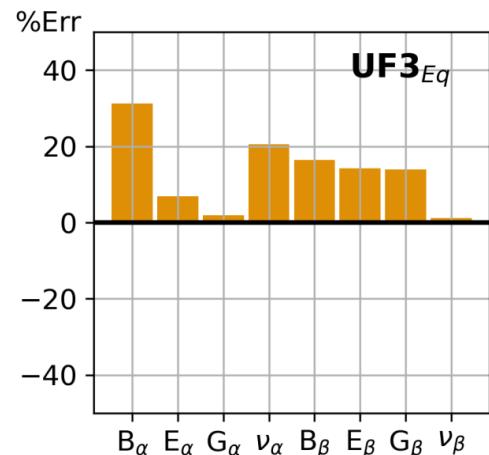
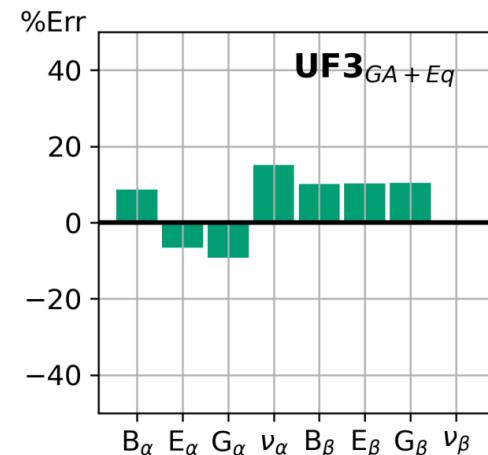
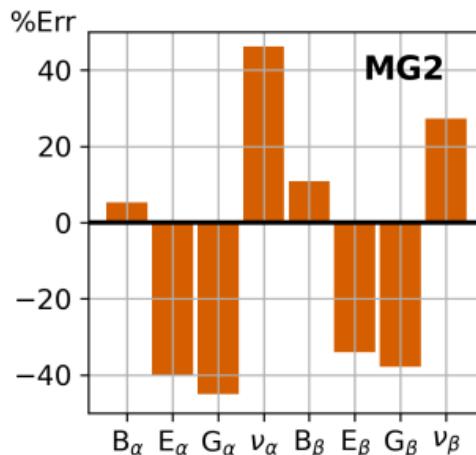
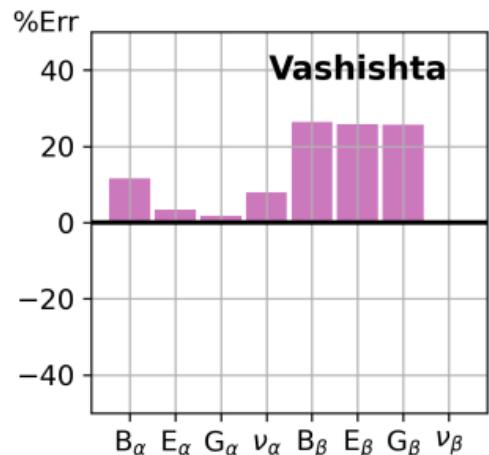
$$\text{Bulk Modulus, } B = -V \frac{dP}{dV}$$

$$\text{Young's Modulus, } E = \frac{\sigma}{\epsilon_{\text{axial}}}$$

$$\text{Shear Modulus, } G = \frac{\tau_{xy}}{\gamma_{xy}}$$

$$\text{Poisson Ratio, } \nu = -\frac{d\epsilon_{\text{transverse}}}{d\epsilon_{\text{axial}}}$$

versus DFT, OK

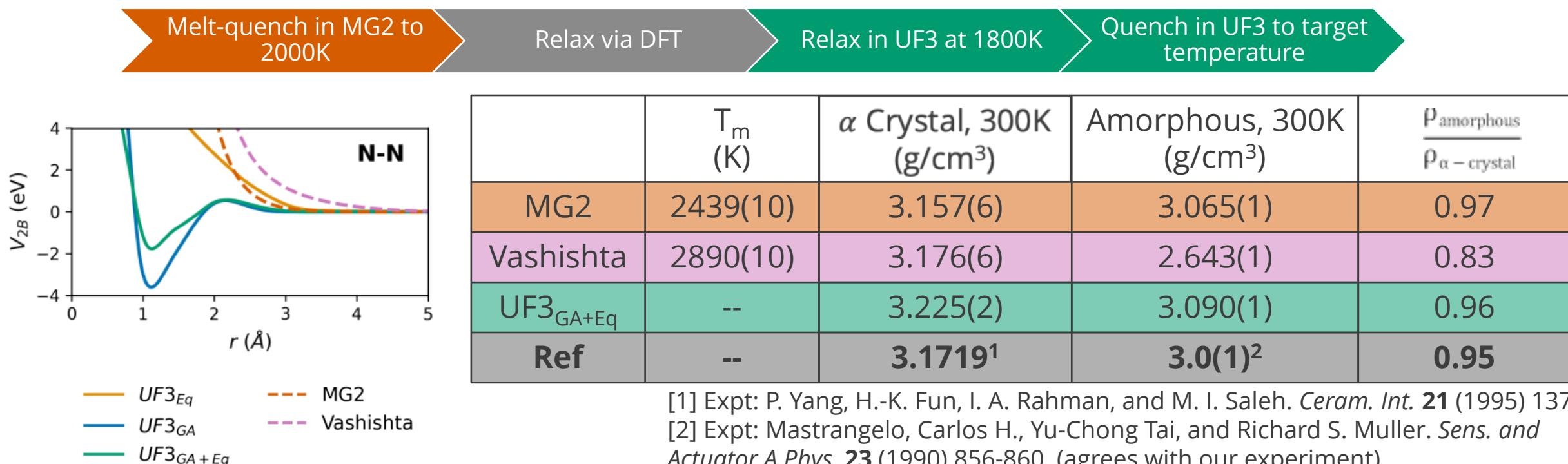


$UF3_{GA+Eq}$ outperforms other models in reproducing mechanical crystal properties.

Structural Properties

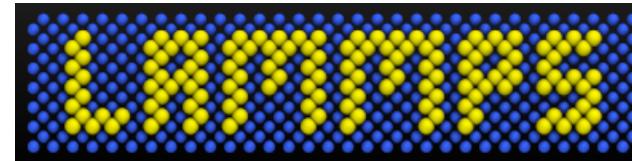
Empirical model amorphous structures are generated using a melt-quench approach.

UF_3_{GA+Eq} (like experiment) forms N2 at high temperatures. Gentle relaxation is required.



UF_3_{GA+Eq} retains high-temperature dissociation behavior
...and reproduces structure well for **both** crystal and amorphous

Crystallization Simulations in



Seeded growth from $\alpha\text{-Si}_3\text{N}_4$

Growth from [0 0 1] and [0 1 0]

Potential-dependent for extrapolation (below T_m)
(1700K, 1750K, 1800K for UF3)

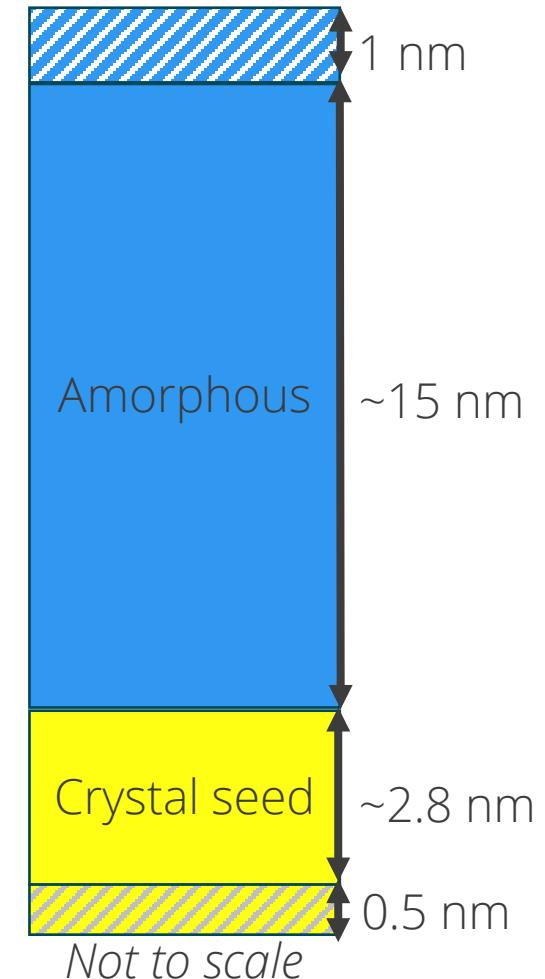
1 bar pressure



“Dynamic” regions fixed to run temperature

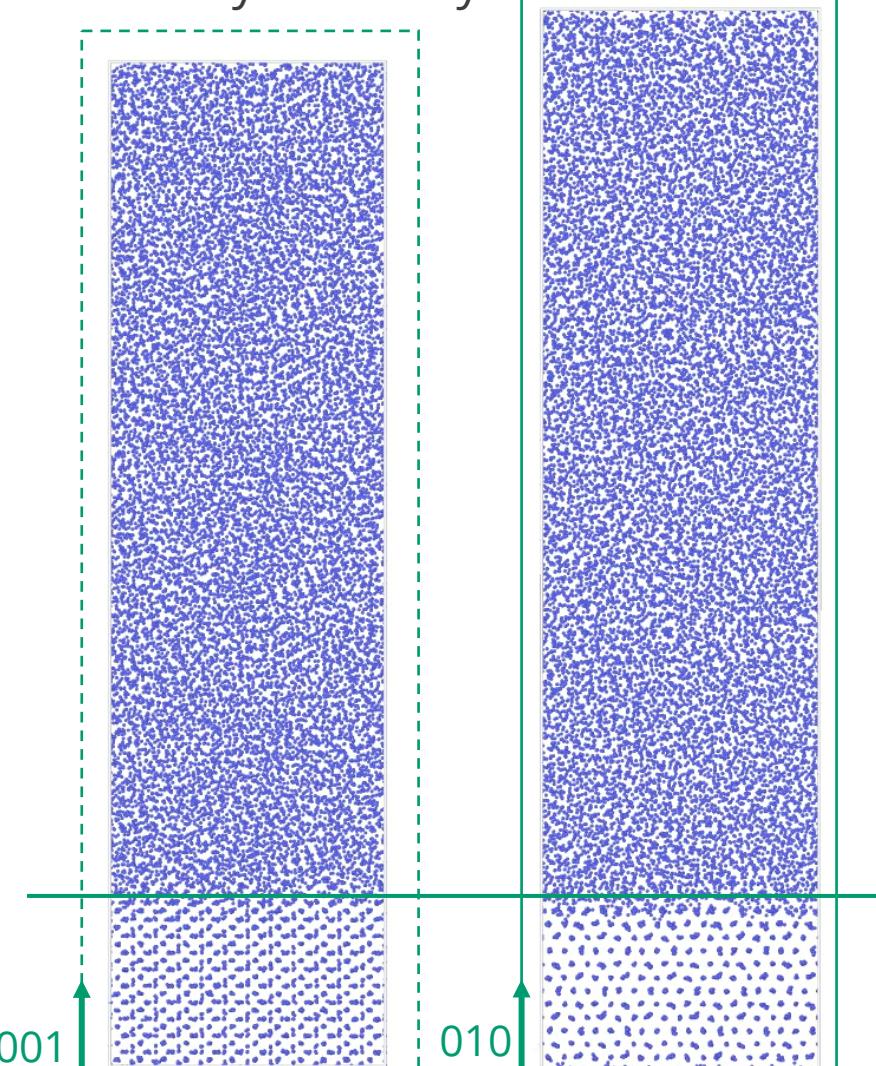


Low-temperature regions fixed to 300K to inhibit growth from periodic interface



UF3 Crystal Growth (Preliminary)

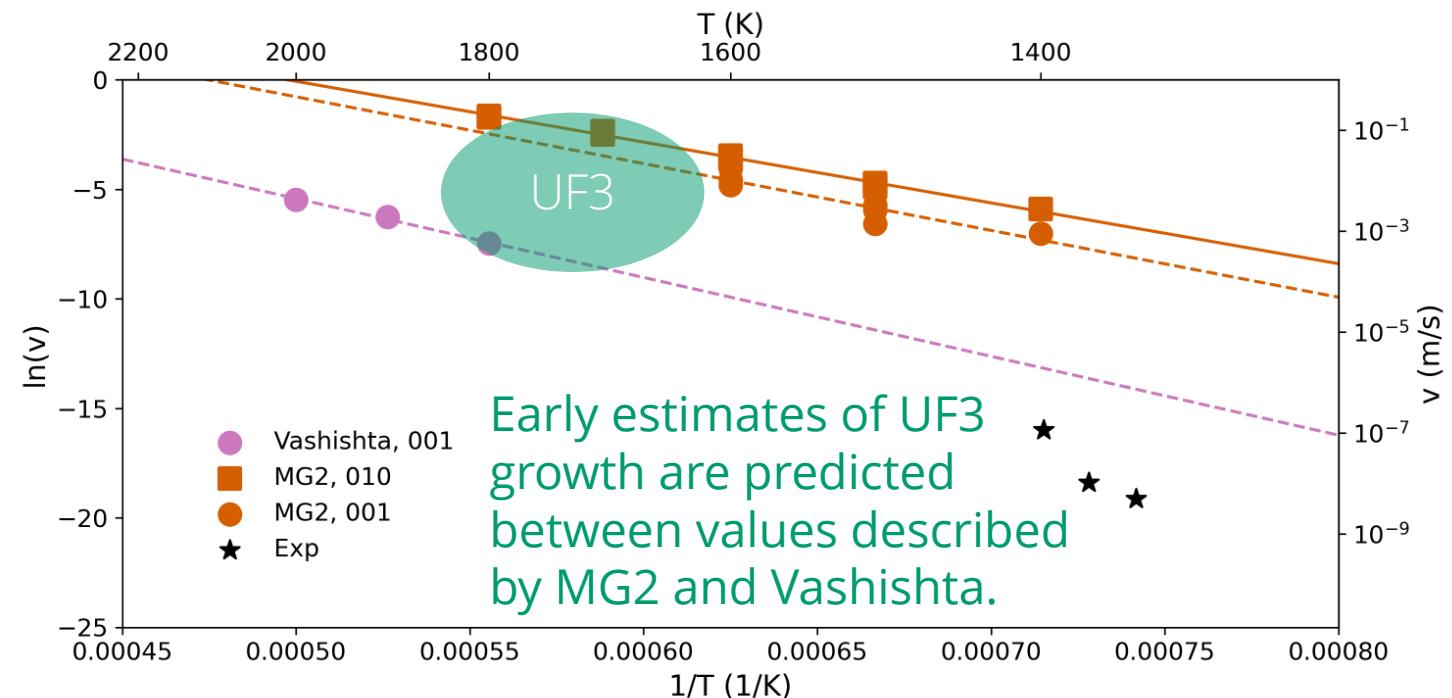
N-atoms only for clarity:



✓ UF3 can model crystallization.

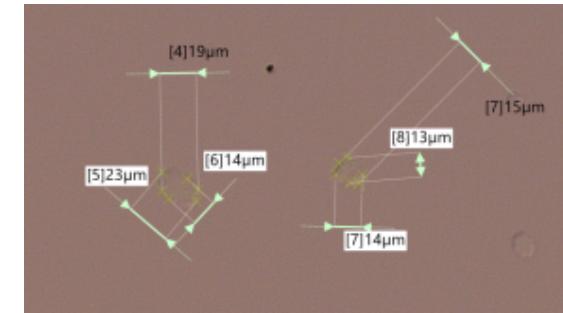
$$\ln(v) = \ln(v_o) - \left(\frac{E_a}{R}\right) \frac{1}{T}$$

T : temperature
 v : velocity
 E_a : activation energy

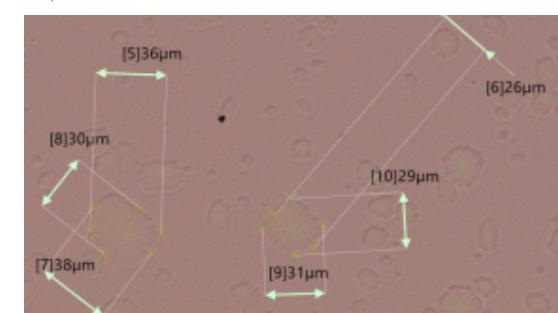


Experimental Comparison Ongoing

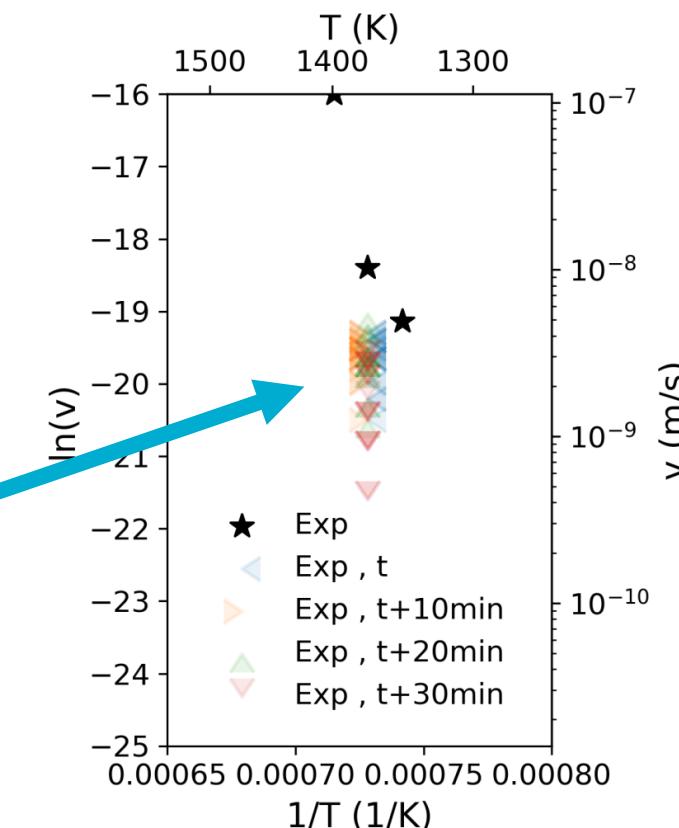
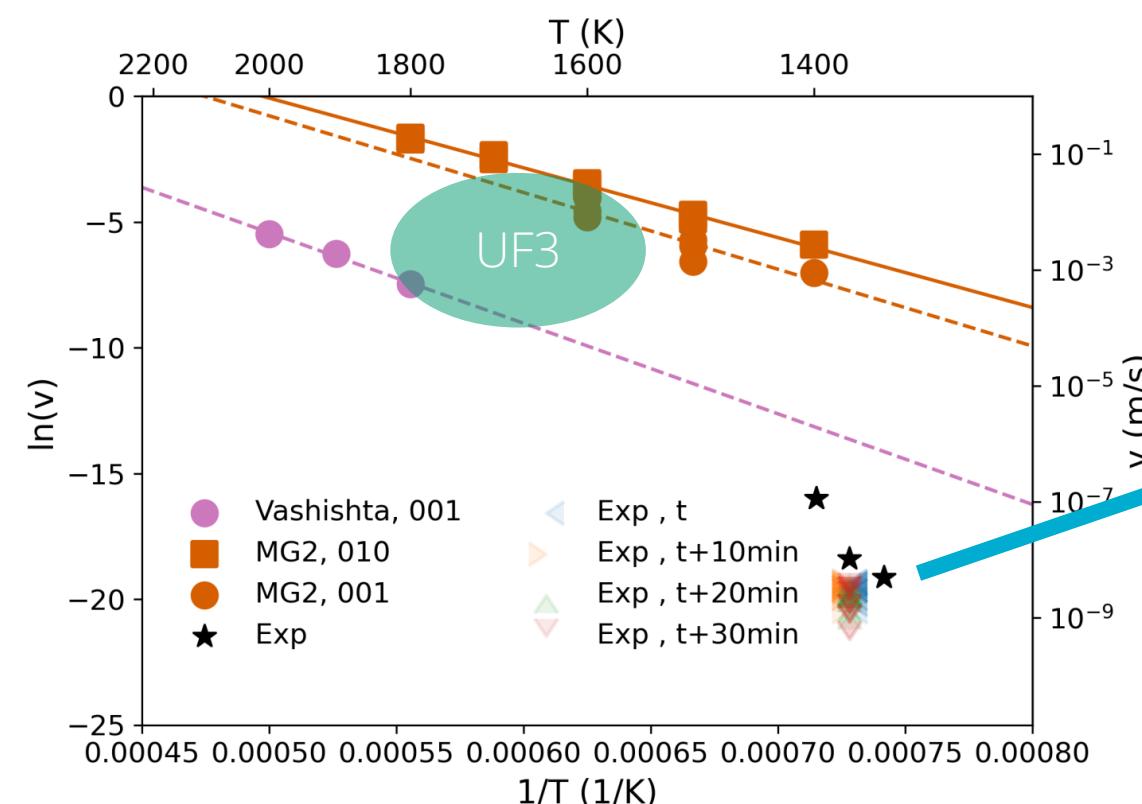
New experiments indicate both **orientational** and **time dependence** in growth.



50 minutes, 1373K



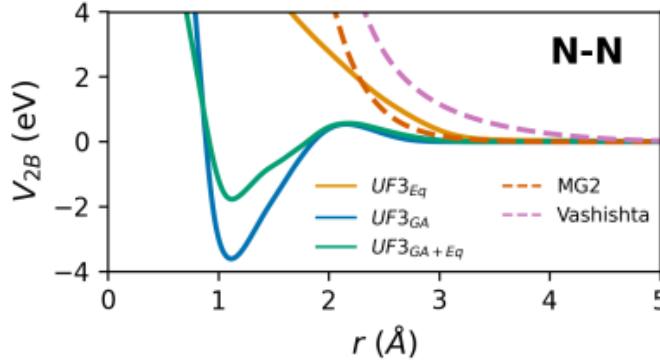
100 μm



Qualitative orientational dependence is reproduced in our models.
Additional characterization is ongoing to assign growth facets to experimental images.

CONCLUSIONS

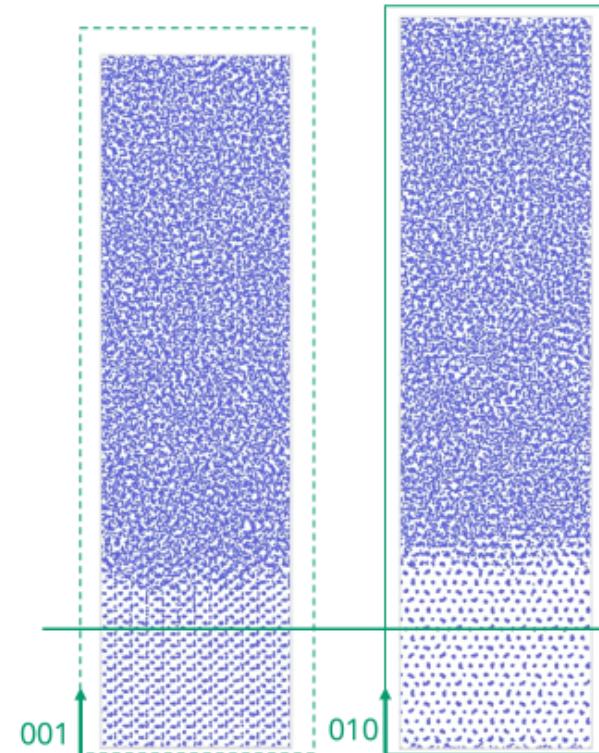
Accurately model structural properties in silicon nitride



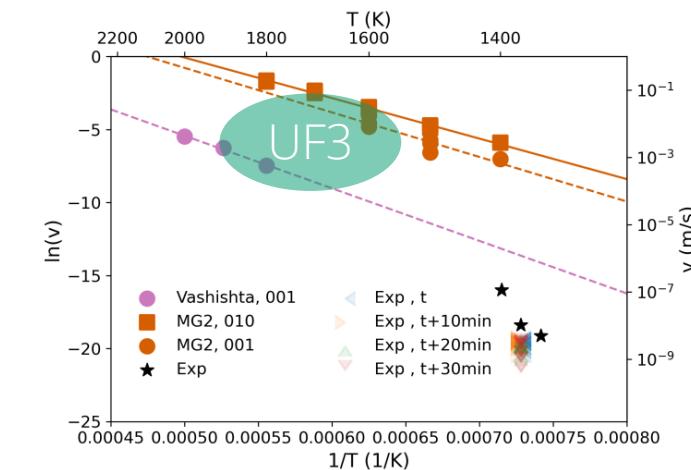
Incorporation of broad training structures enables exploration of physical phase space not possible for existing empirical models.

Show that we can reproduce experimental growth behaviors

Orientational growth rate dependence *qualitatively* agrees with experiment.



Extract mechanistic details where possible

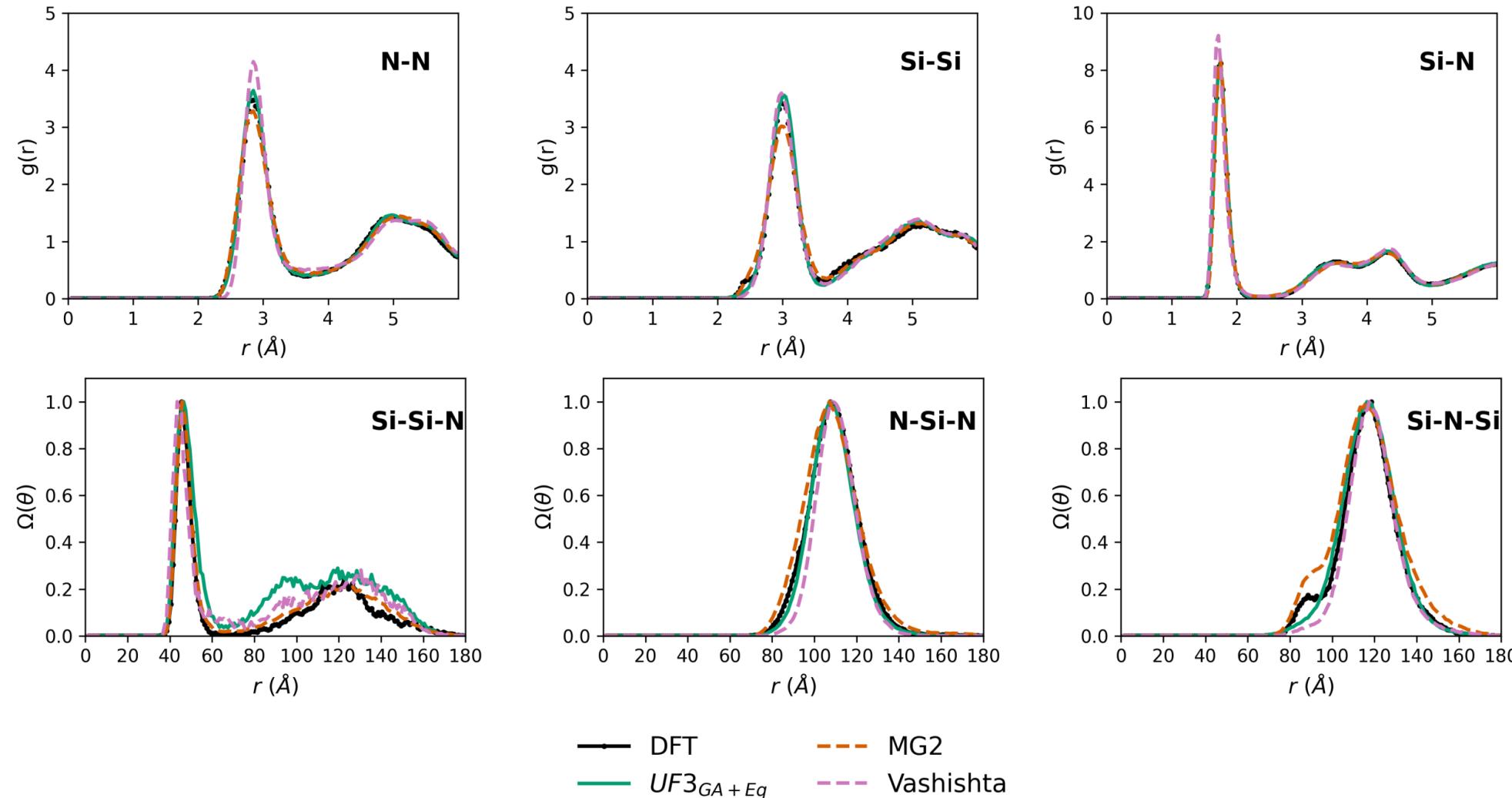


Quantification of growth mechanism is ongoing.

Future work:

- Add stress, impurities
- Incorporate defects

Additional Amorphous Structural Properties

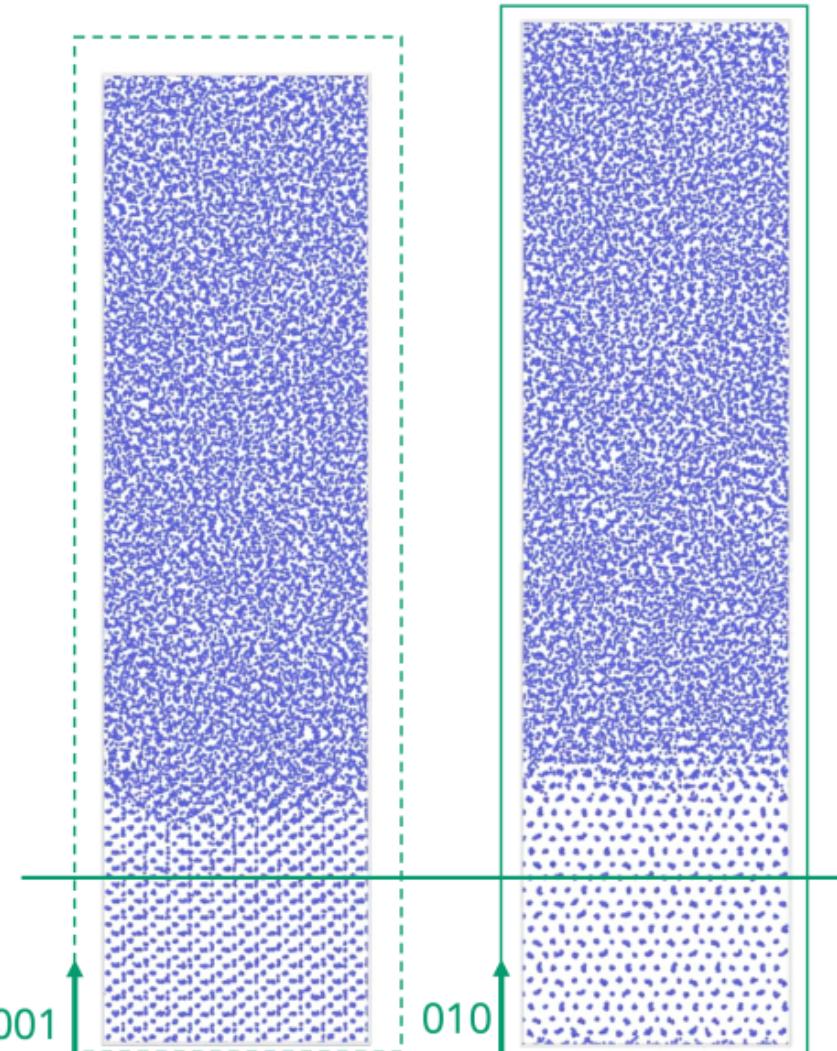


All models reproduce amorphous distributions well; MG2 and UF3 perform slightly better in low-angle Si-N-Si angle values.



UF3 Crystal Growth (Preliminary)

N-atoms only for clarity:



✓ UF3 can model crystallization.

Quantifying growth rates enables experimental comparison

Interfaces are defined as a transition in the potential energy profile along the direction of growth.

